

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/527,062	FURUISHI ET AL.
	<b>Examiner</b> Nyeemah Grazier	<b>Art Unit</b> 1626

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
STN structure search	2/28/2007	NG
IDS	2/28/2007	NG
Inventor Name Search	2/28/2007	NG

<b>INTERFERENCE SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>